

Fig. 1A

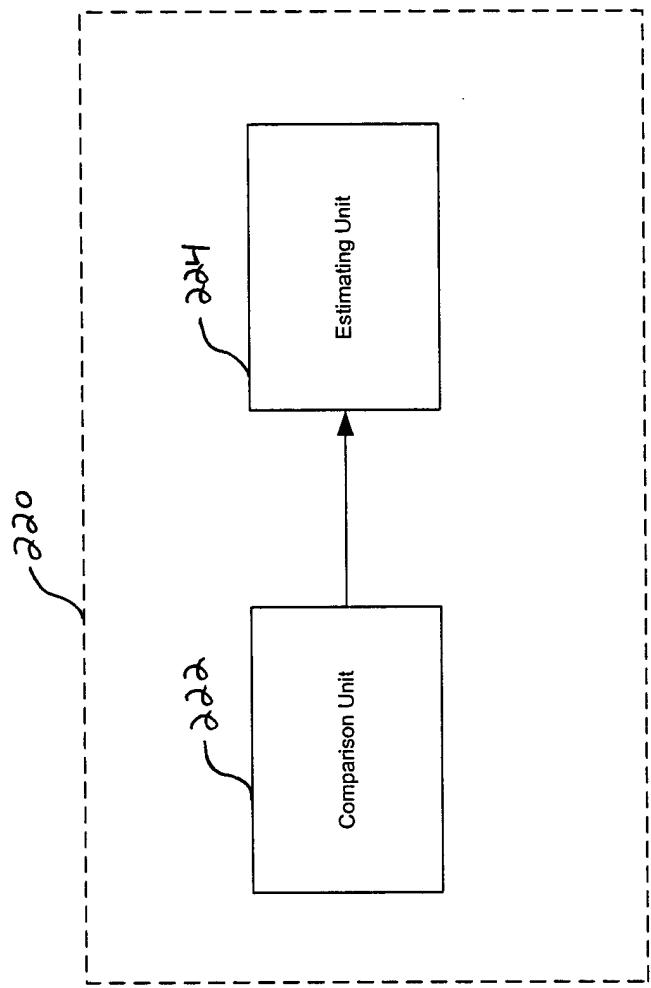
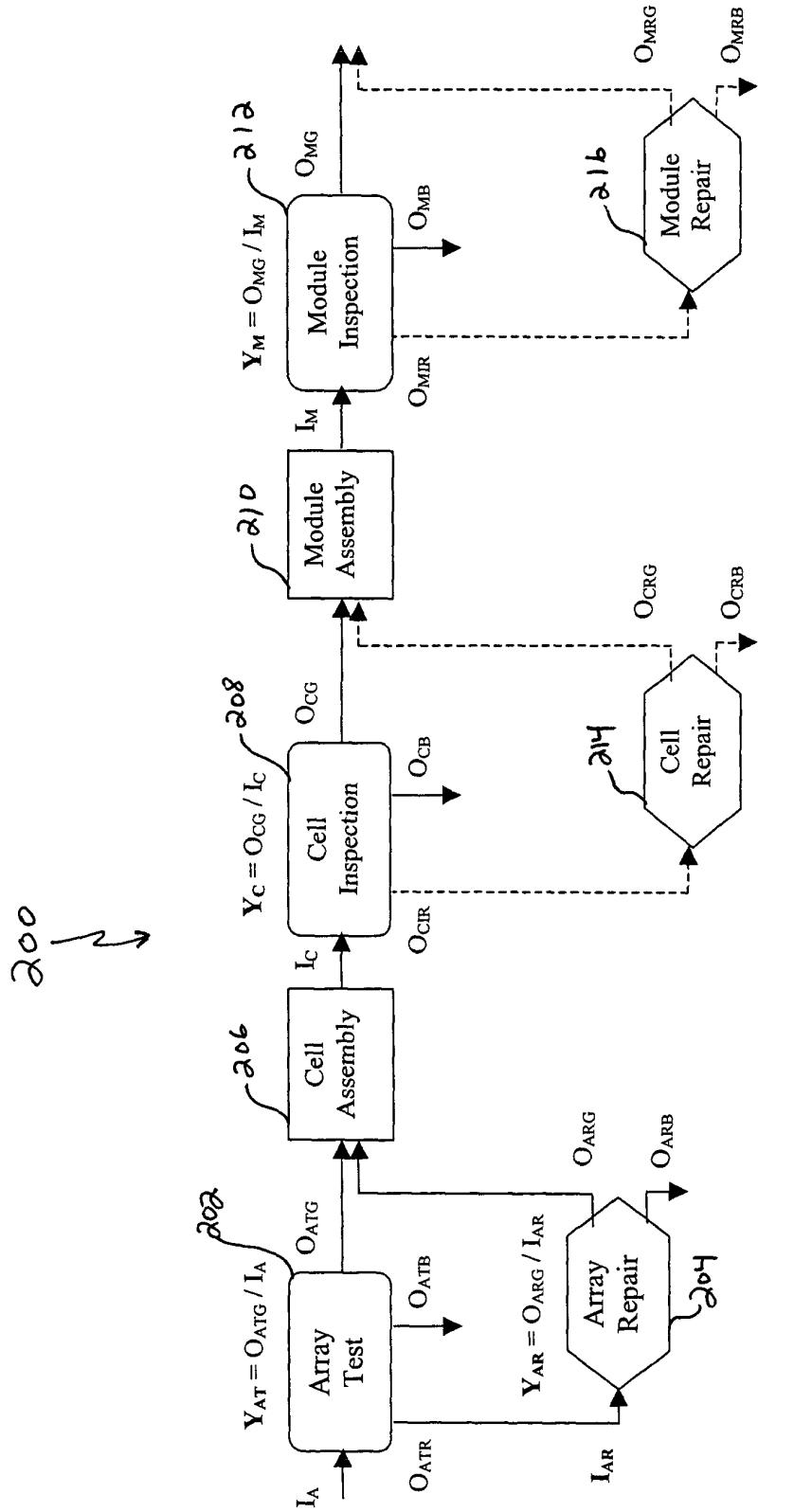


Fig. 1B



→ Normal production flow
 → Optional production flow including cell and/or module repairs

Fig. 2

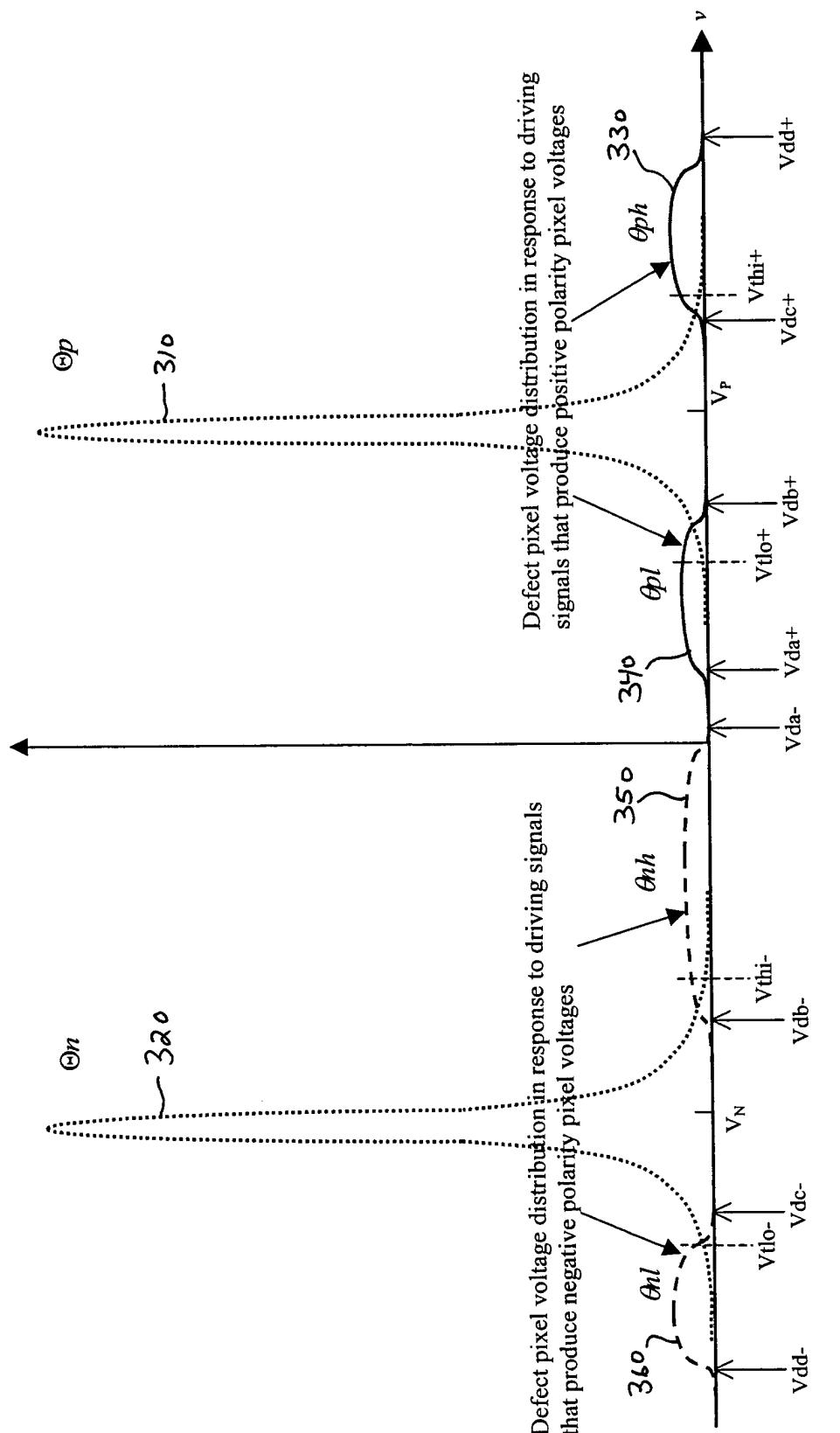


Fig. 3A

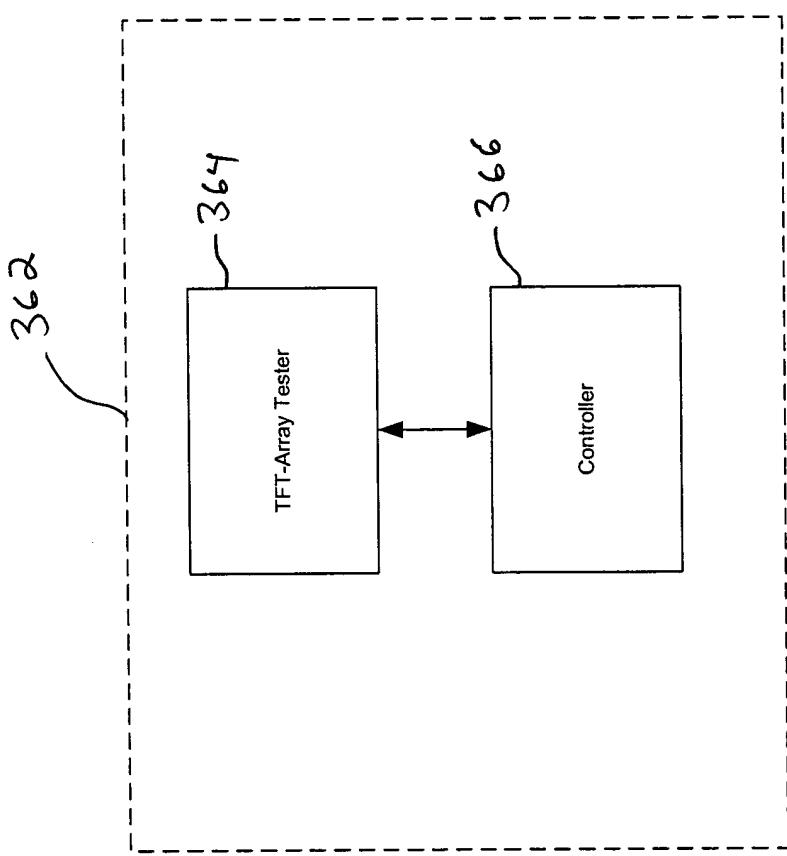
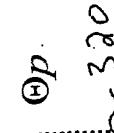


Fig. 3B

(1) Sensor measurement with small standard deviation, σ_p .



Defective pixels in this region are not detected by TFT-array tester and become under-killed defects.

Defective pixels in this region are not detected by TFT-array tester and become under-killed defects.

(2) Sensor measurement with large standard deviation, σ_p .

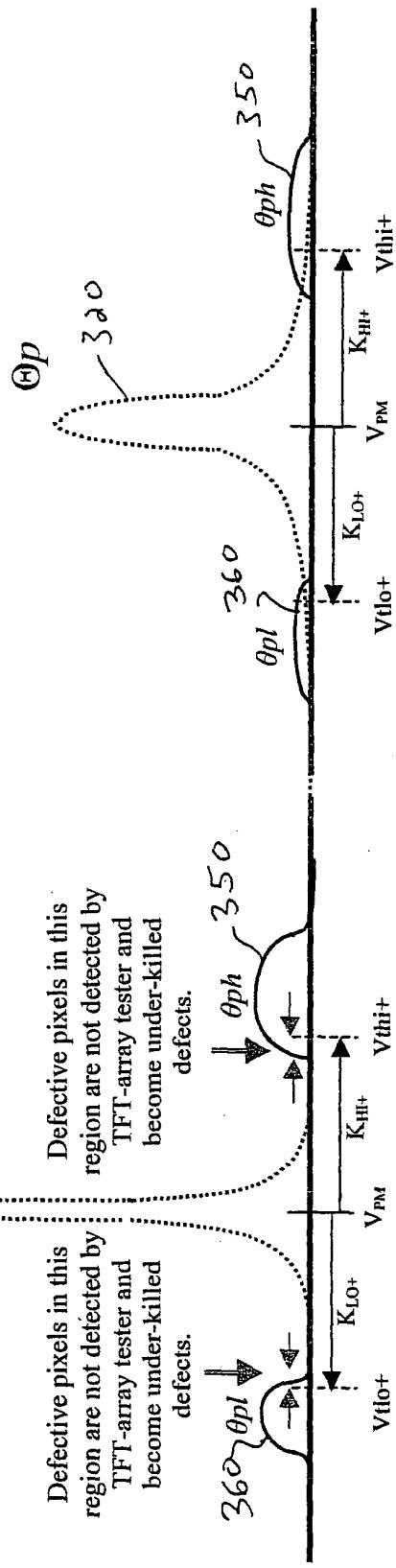
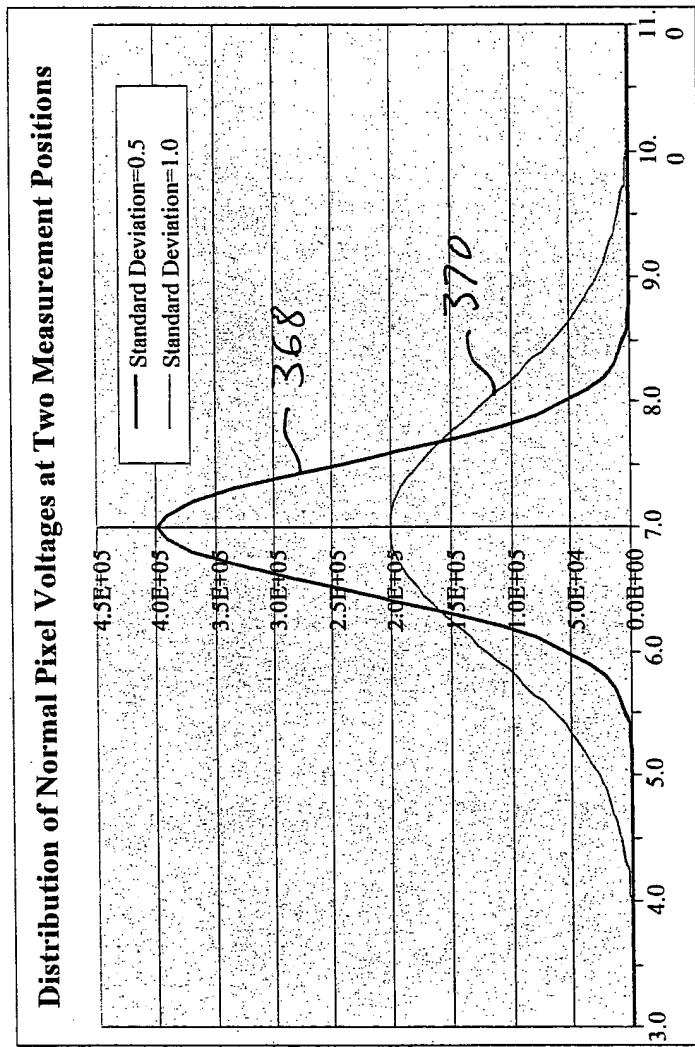
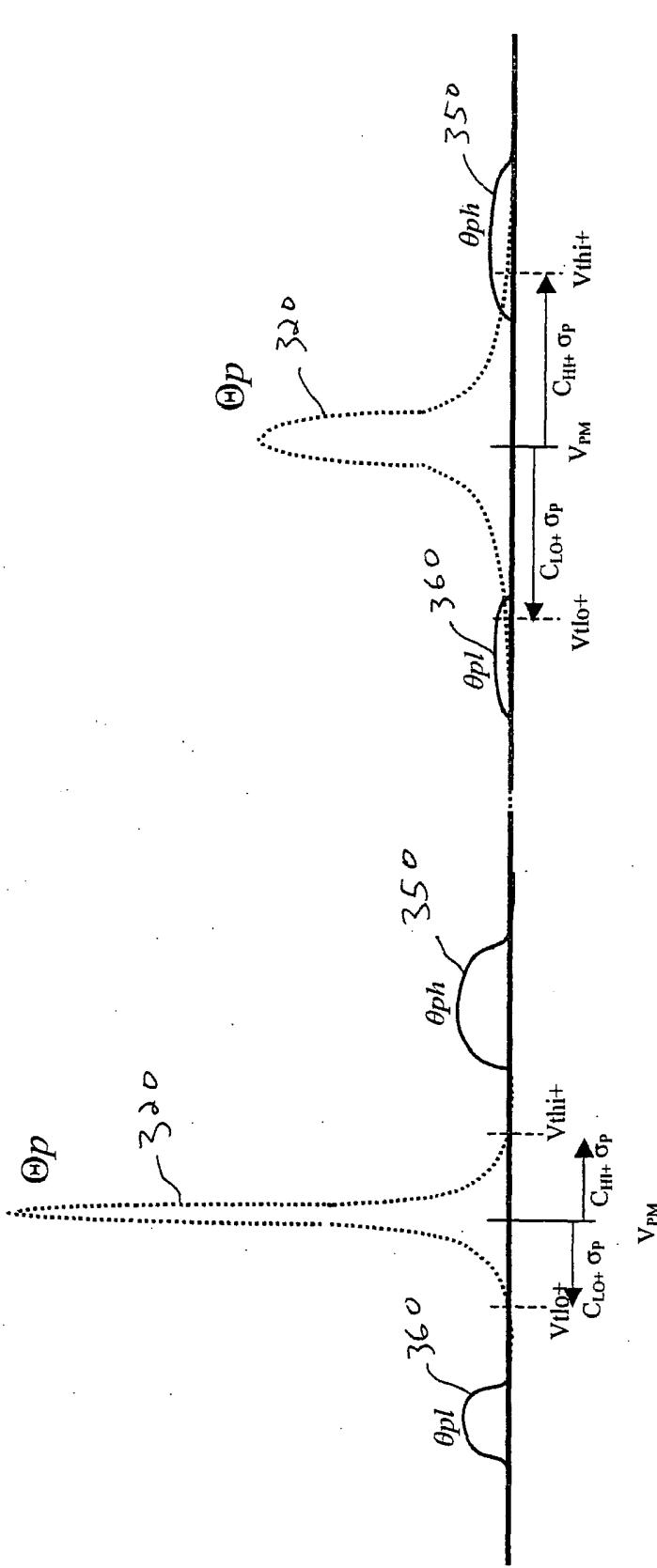


Fig. 3C

Fig. 3D



(1) Sensor measurement with small standard deviation, σ_p .



(2) Sensor measurement with large standard deviation, σ_p .

Fig. 3E

Fig. 3F

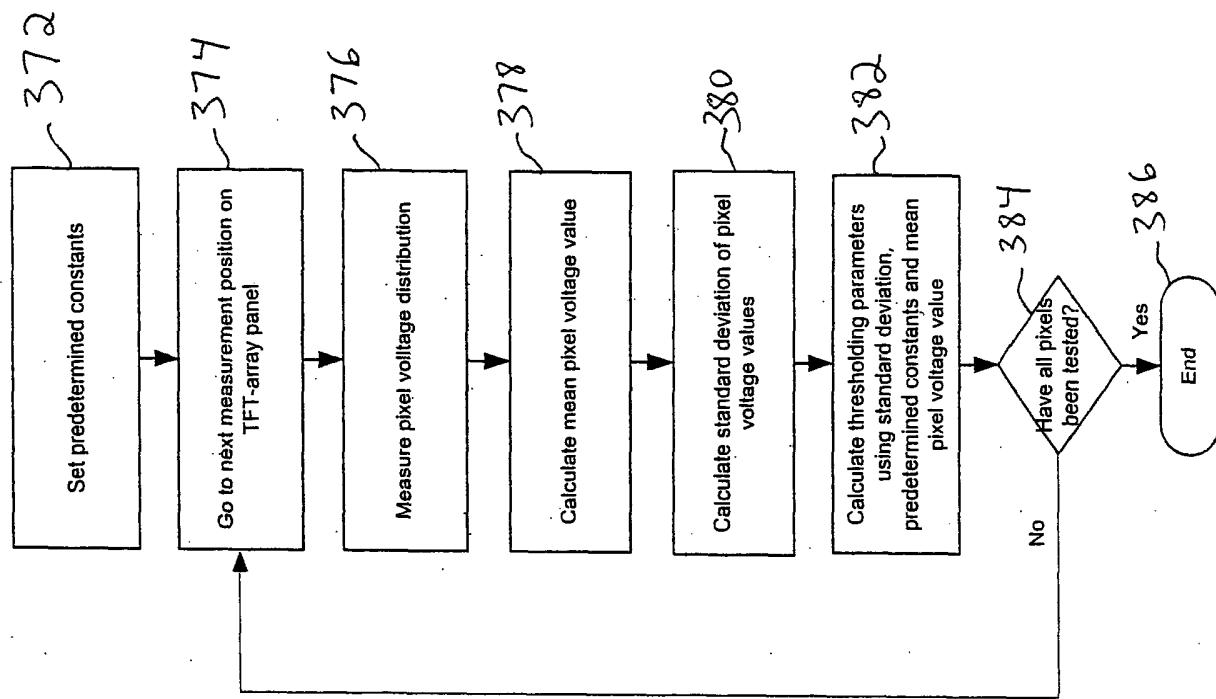


Fig. 4

